

Electromagnetic compatibility (EMC) -- Part 4-6: Testing and measurement techniques - Immunity to conducted disturbances, induced by radio-frequency fields

EESTI STANDARDI EESSÕNA

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**Electromagnetic compatibility (EMC) -
Part 4-6: Testing and measurement techniques -
Immunity to conducted disturbances, induced by radio-frequency fields
(IEC 61000-4-6:2013)**

Compatibilité électromagnétique (CEM) -
Partie 4-6: Techniques d'essai et de
mesure - Immunité aux perturbations
conduites, induites par les champs
radioélectriques
(CEI 61000-4-6:2013)

Elektromagnetische Verträglichkeit (EMV)
- Teil 4-6: Prüf- und Messverfahren -
Störfestigkeit gegen leitungsgeführte
Störgrößen, induziert durch hochfrequente
Felder
(IEC 61000-4-6:2013)

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

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Foreword

The text of document 77B/691/FDIS, future edition 4 of IEC 61000-4-6, prepared by SC 77B "High frequency phenomena" of IEC/TC 77 "Electromagnetic compatibility" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 61000-4-6:2014.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2014-08-27
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2016-11-27

This document supersedes EN 61000-4-6:2009.

EN 61000-4-6:2014 includes the following significant technical changes with respect to EN 61000-4-6:2009:

- a) use of the CDNs;
- b) calibration of the clamps;
- c) reorganization of Clause 7 on test setup and injection methods;
- d) Annex A which is now dedicated to EM and decoupling clamps;
- e) Annex G which now addresses the measurement uncertainty of the voltage test level;
- f) informative Annexes H, I and J which are new.

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Endorsement notice

The text of the International Standard IEC 61000-4-6:2013 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following notes have to be added for the standards indicated:

IEC 61000-4-3	NOTE	Harmonised as EN 61000-4-3.
CISPR 16-1-2	NOTE	Harmonised as EN 55016-1-2.
CISPR 16-1-4	NOTE	Harmonised as EN 55016-1-4.
CISPR 20	NOTE	Harmonised as EN 55020.

Annex ZA
(normative)

**Normative references to international publications
with their corresponding European publications**

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60050 (Series)	-	International Electrotechnical Vocabulary (IEV)	-	-

CONTENTS

FOREWORD.....	5
INTRODUCTION.....	7
1 Scope.....	8
2 Normative references	8
3 Terms and definitions	8
4 General.....	10
5 Test levels.....	12
6 Test equipment and level adjustment procedures	13
6.1 Test generator	13
6.2 Coupling and decoupling devices	15
6.2.1 General	15
6.2.2 Coupling/decoupling networks (CDNs).....	18
6.2.3 Clamp injection devices	20
6.2.4 Direct injection devices.....	22
6.2.5 Decoupling networks	22
6.3 Verification of the common mode impedance at the EUT port of coupling and decoupling devices.....	23
6.3.1 General	23
6.3.2 Insertion loss of the 150 Ω to 50 Ω adapters	23
6.4 Setting of the test generator.....	25
6.4.1 General	25
6.4.2 Setting of the output level at the EUT port of the coupling device.....	26
7 Test setup and injection methods	28
7.1 Test setup.....	28
7.2 EUT comprising a single unit.....	28
7.3 EUT comprising several units.....	29
7.4 Rules for selecting injection methods and test points	30
7.4.1 General	30
7.4.2 Injection method	30
7.4.3 Ports to be tested	31
7.5 CDN injection application	32
7.6 Clamp injection application when the common mode impedance requirements can be met.....	33
7.7 Clamp injection application when the common mode impedance requirements cannot be met.....	35
7.8 Direct injection application	35
8 Test procedure	36
9 Evaluation of the test results	37
10 Test report.....	37
Annex A (normative) EM and decoupling clamps.....	39
Annex B (informative) Selection criteria for the frequency range of application	49
Annex C (informative) Guide for selecting test levels	51
Annex D (informative) Information on coupling and decoupling networks	52
Annex E (informative) Information for the test generator specification	57
Annex F (informative) Test setup for large EUTs.....	58

Annex G (informative) Measurement uncertainty of the voltage test level	61
Annex H (informative) Measurement of AE impedance	72
Annex I (informative) Port to port injection	76
Annex J (informative) Amplifier compression and non-linearity	78
Bibliography	83
Figure 1 – Immunity test to RF conducted disturbances	12
Figure 2 – Open circuit waveforms at the EUT port of a coupling device for test level 1	13
Figure 3 – Test generator setup	15
Figure 4 – Principle of coupling and decoupling	18
Figure 5 – Principle of coupling and decoupling according to the clamp injection method	20
Figure 6 – Example of circuit for level setting setup in a 150 Ω test jig	21
Figure 7 – Example circuit for evaluating the performance of the current clamp	22
Figure 8 – Details of setups and components to verify the essential characteristics of coupling and decoupling devices and the 150 Ω to 50 Ω adapters	25
Figure 9 – Setup for level setting	27
Figure 10 – Example of test setup with a single unit EUT (top view)	29
Figure 11 – Example of a test setup with a multi-unit EUT (top view)	30
Figure 12 – Rules for selecting the injection method	31
Figure 13 – Immunity test to 2-port EUT (when only one CDN can be used)	33
Figure 14 – General principle of a test setup using clamp injection devices	34
Figure 15 – Example of the test unit locations on the ground plane when using injection clamps (top view)	35
Figure A.1 – Example: Construction details of the EM clamp	40
Figure A.2 – Example: Concept of the EM clamp	41
Figure A.3 – Dimension of a reference plane	42
Figure A.4 – Test jig	42
Figure A.5 – Test jig with inserted clamp	42
Figure A.6 – Impedance / decoupling factor measurement setup	43
Figure A.7 – Typical examples for clamp impedance, 3 typical clamps	44
Figure A.8 – Typical examples for decoupling factors, 3 typical clamps	45
Figure A.9 – Normalization setup for coupling factor measurement	45
Figure A.10 – S_{21} coupling factor measurement setup	46
Figure A.11 – Typical examples for coupling factor, 3 typical clamps	46
Figure A.12 – Decoupling clamp characterization measurement setup	47
Figure A.13 – Typical examples for the decoupling clamp impedance	47
Figure A.14 – Typical examples for decoupling factors	48
Figure B.1 – Start frequency as function of cable length and equipment size	50
Figure D.1 – Example of a simplified diagram for the circuit of CDN-S1 used with screened cables (see 6.2.2.5)	53
Figure D.2 – Example of simplified diagram for the circuit of CDN-M1/-M2/-M3 used with unscreened supply (mains) lines (see 6.2.2.2)	53
Figure D.3 – Example of a simplified diagram for the circuit of CDN-AF2 used with unscreened unbalanced lines (see 6.2.2.4)	54

Figure D.4 – Example of a simplified diagram for the circuit of a CDN-T2, used with an unscreened balanced pair (see 6.2.2.3)	54
Figure D.5 – Example of a simplified diagram of the circuit of a CDN-T4 used with unscreened balanced pairs (see 6.2.2.3)	55
Figure D.6 – Example of a simplified diagram of the circuit of a CDN AF8 used with unscreened unbalanced lines (see 6.2.2.4)	55
Figure D.7 – Example of a simplified diagram of the circuit of a CDN-T8 used with unscreened balanced pairs (see 6.2.2.3)	56
Figure F.1 – Example of large EUT test setup with elevated horizontal reference ground plane	59
Figure F.2 – Example of large EUT test setup with vertical reference ground plane	60
Figure G.1 – Example of influences upon voltage test level using CDN	62
Figure G.2 – Example of influences upon voltage test level using EM clamp	62
Figure G.3 – Example of influences upon voltage test level using current clamp	63
Figure G.4 – Example of influences upon voltage test level using direct injection	63
Figure G.5 – Circuit for level setting setup	64
Figure H.1 – Impedance measurement using a voltmeter	73
Figure H.2 – Impedance measurement using a current probe	74
Figure I.1 – Example of setup, port-port injection	77
Figure J.1 – Amplifier linearity measurement setup	80
Figure J.2 – Linearity characteristic	81
Figure J.3 – Measurement setup for modulation depth	81
Figure J.4 – Spectrum of AM modulated signal	82
Table 1 – Test levels	13
Table 2 – Characteristics of the test generator	14
Table 3 – Main parameter of the combination of the coupling and decoupling device	15
Table 4 – Usage of CDNs	18
Table B.1 – Main parameter of the combination of the coupling and decoupling device when the frequency range of test is extended above 80 MHz	49
Table E.1 – Required power amplifier output power to obtain a test level of 10 V	57
Table G.1 – CDN level setting process	65
Table G.2 – CDN test process	65
Table G.3 – EM clamp level setting process	67
Table G.4 – EM clamp test process	67
Table G.5 – Current clamp level setting process	68
Table G.6 – Current clamp test process	69
Table G.7 – Direct injection level setting process	70
Table G.8 – Direct injection test process	70
Table H.1 – Impedance requirements for the AE	72
Table H.2 – Derived voltage division ratios for AE impedance measurements	73
Table H.3 – Derived voltage ratios for AE impedance measurements	74

INTRODUCTION

IEC 61000 is published in separate parts according to the following structure:

Part 1: General

General considerations (introduction, fundamental principles)

Definitions, terminology

Part 2: Environment

Description of the environment

Classification of the environment

Compatibility levels

Part 3: Limits

Emission limits

Immunity limits (in so far as they do not fall under the responsibility of the product committees)

Part 4: Testing and measurement techniques

Measurement techniques

Testing techniques

Part 5: Installation and mitigation guidelines

Installation guidelines

Mitigation methods and devices

Part 6: Generic standards

Part 9: Miscellaneous

Each part is further subdivided into several parts, published either as international standards or as technical specifications or technical reports, some of which have already been published as sections. Others will be published with the part number followed by a dash and a second number identifying the subdivision (example: IEC 61000-6-1).

This part is an international standard which gives immunity requirements and test procedures related to conducted disturbances induced by radio-frequency fields.